

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/760,555 <b>Examiner</b> CongVan Tran	<b>Applicant(s)/Patent under Reexamination</b> LEE ET AL. <b>Art Unit</b> 2617
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner